US 20170030772A1

(19) United States

(12) Patent Application Publication

(10) Pub. No.: US 2017/0030772 A1

(43) Pub. Date: Feb. 2, 2017

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(54) **APPARATUS AND METHOD FOR VERIFYING REPEATABILITY OF SPECTROSCOPE, AND APPARATUS FOR ANALYZING SPECTRUM DATA**

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(21) Appl. No.: **15/215,050**

(22) Filed: **Jul. 20, 2016**

(30) **Foreign Application Priority Data**

Jul. 30, 2015 (KR) 10-2015-0108288

Publication Classification

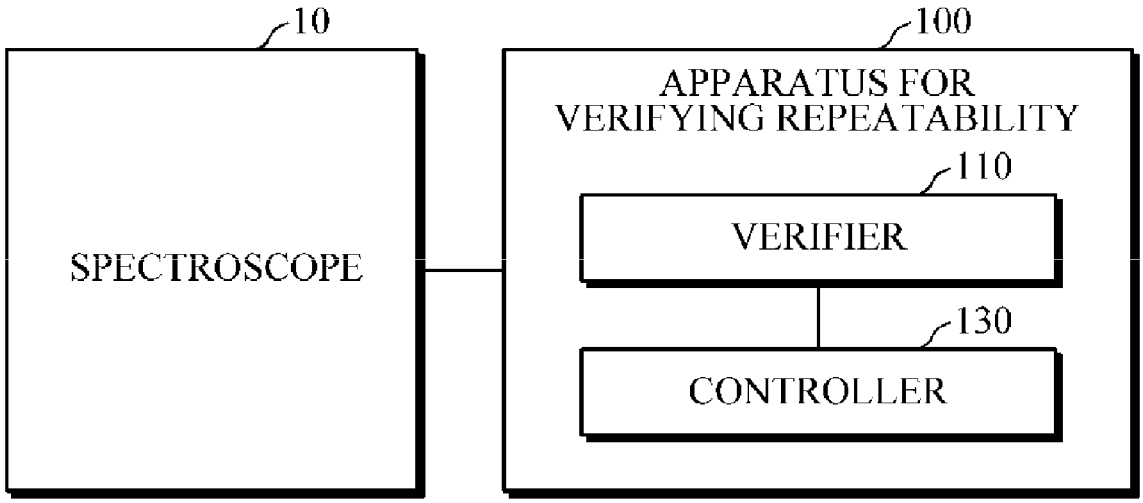
(51) **Int. Cl.**

G01J 3/02 (2006.01)

G01J 3/28 (2006.01)

(52) **U.S. Cl.**

CPC . ***G01J 3/027*** (2013.01); ***G01J 3/28*** (2013.01)

(57) **ABSTRACT**

An apparatus for verifying repeatability of a spectroscope may verify repeatability of spectrum data, measured by a spectroscope, based on repeatability verification criteria, and control the spectroscope whether or not to remeasure spectrum data.